

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re application of: Shing M. Lee

Attorney Docket No.:  
KLA1P012/P647US

Application No.: 09/695,726

Examiner: Fernandez, K.

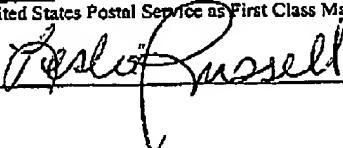
Filed: October 23, 2000

Group: 2881

Title: **FILM THICKNESS MEASUREMENT  
USING ELECTRON-BEAM INDUCED X-  
RAY MICROANALYSIS**CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service as First Class Mail to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on October 2, 2003.

Printed Name: Leslie Russell

Signed: RESPONSE ECommissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450**RECEIVED  
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Dear Sir:

In response to the Office Action dated July 8, 2003, a response to which is due on October 8, 2003, please consider the following amendments and remarks:

Amendments to the Claims are reflected in the listing of claims which begins on page 2 of this paper.

Remarks/Arguments begin on page 7 of this paper.